

Main application

- Secure digital memory card in mobile phones and communication systems

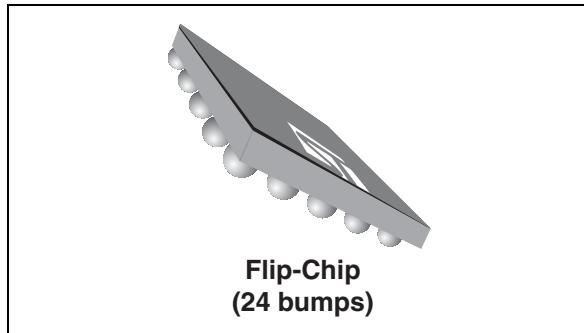
Description

The EMIF09-SD01F3 is a highly integrated array designed to suppress EMI/RFI noise for secure digital memory cards. The EMIF09-SD01F3 is in a flip chip package to offer space saving and high RF performance.

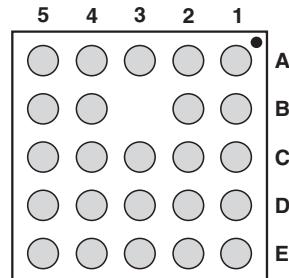
This low-pass filter includes ESD protection circuitry, which prevents damage to the protected device when subjected to ESD surges up 15 kV. This filter also has a low line capacitance to be compatible with high data rate signals.

Benefits

- 9 line EMI low-pass filter and ESD protection
- High efficiency in EMI filtering
- Lead free package
- 400 µm pitch
- Very low PCB space consumption: < 4 mm²
- Very thin package: 0.6 mm
- High reliability offered by monolithic integration
- Reduction of parasitic elements thanks to CSP integration.



Pin Configuration (bump side)



Complies with the following standards:

IEC 61000-4-2:

- Level 4 on external pins 15 kV (air discharge)
8 kV (contact discharge)
Level 2 on internal pins 2 kV (air discharge)
2 kV (contact discharge)

MIL STD 833F - Method 3015.7 Class 3

PIN	DESCRIPTION								
A1	DATA2	B1	CD	C1	DAT3_PD	D1	WP+CD	E1	DATA1
A2	DATA3	B2	CMD	C2	WP	D2	CLK	E2	DATA0
A3	GND_H	B3		C3	DAT3_PU	D3	GND_C	E3	GND_C
A4	SDDATA2	B4	SDCD	C4	SDWP	D4	SDWP+CD	E4	SDDATA1
A5	SDDATA3	B5	SDCMD	C5	VSD	D5	SDCLK	E5	SDDATA0

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1 Characteristics

Figure 1. Configuration

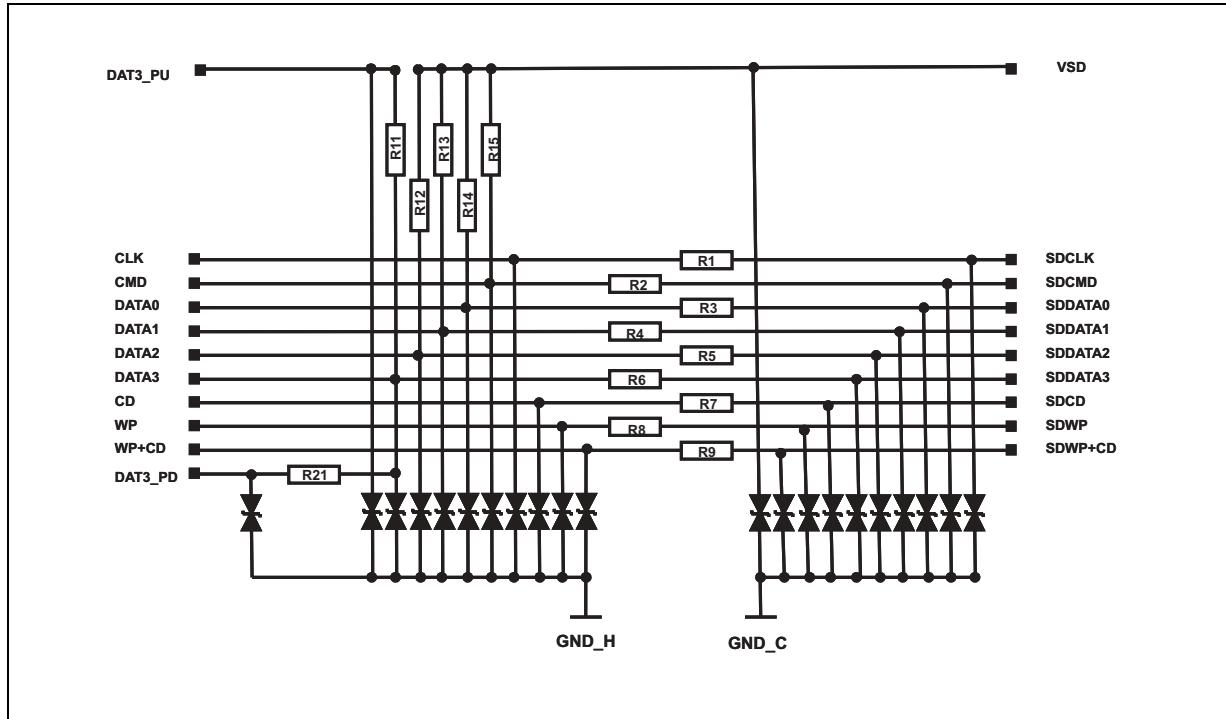


Table 1. Absolute Maximum Ratings

Symbol	Parameter	Value	Unit
V_{PP}	Internal pins (A1, B1, C1, D1, E1, A2, B2, C2, D2, E2, C3) ESD discharge IEC 61000-4-2, air discharge	2	kV
	ESD discharge IEC 61000-4-2, contact discharge	2	
External pins (A4, B4, C4, D4, E4, A5, B5, C5, D5, E5) ESD discharge IEC 61000-4-2, air discharge	15		
	ESD discharge IEC 61000-4-2, contact discharge		8
T_j	Junction temperature	125	°C
T_{op}	Operating temperature range	-30 to + 85	°C
T_{stg}	Storage temperature range	-55 to 150	°C

GND bumps (GND_H and GND_C - A3, D3 and E3) must be connected to ground on the printed circuit board for ESD testing and RF measurements.

1.1 Electrical characteristics ($T_{amb} = 25^\circ C$)

Symbol	Parameter
V_{BR}	Breakdown voltage
I_{RM}	Leakage current @ V_{RM}
V_{RM}	Stand-off voltage
V_{CL}	Clamping voltage
I_{PP}	Peak pulse current
R_d	Dynamic impedance
$R_{I/O}$	Series resistance between Input & Output
C_{line}	Input capacitance per line

Symbol	Test conditions	Min.	Typ.	Max.	Unit
V_{BR}	$I_R = 1 \text{ mA}$	14			V
I_{RM}	$V_{RM} = 5 \text{ V per line}$			0.5	μA
R1, R2, R3, R4, R5, R6, R7, R8, R9	Tolerance $\pm 20\%$		40		Ω
R11, R12, R13, R14	Tolerance $\pm 30\%$		50		$k\Omega$
R15	Tolerance $\pm 30\%$		15		$k\Omega$
R21	Tolerance $\pm 30\%$		470		$k\Omega$
C_{line}	$V_{line} = 0\text{V}, V_{OSC} = 30 \text{ mV}, F = 1 \text{ MHz}$ (under zero light conditions)			20	pF

Figure 2. S21(db) all lines attenuation measurement

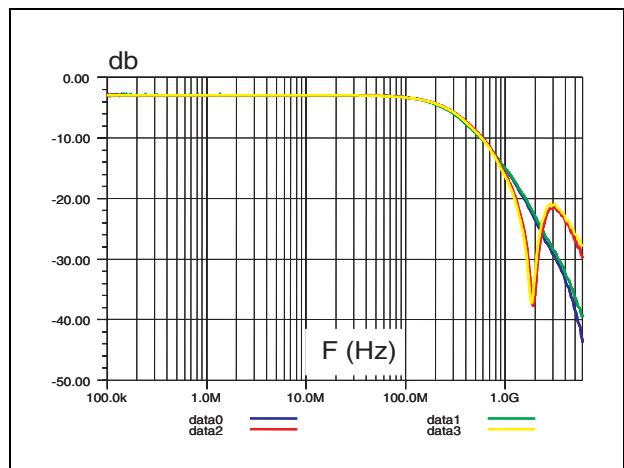


Figure 3. Analog cross talk measurements

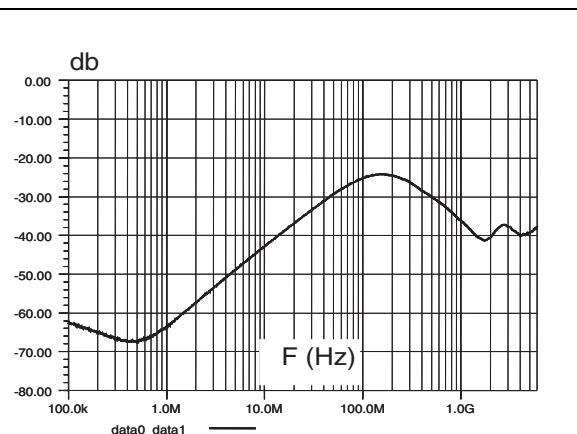


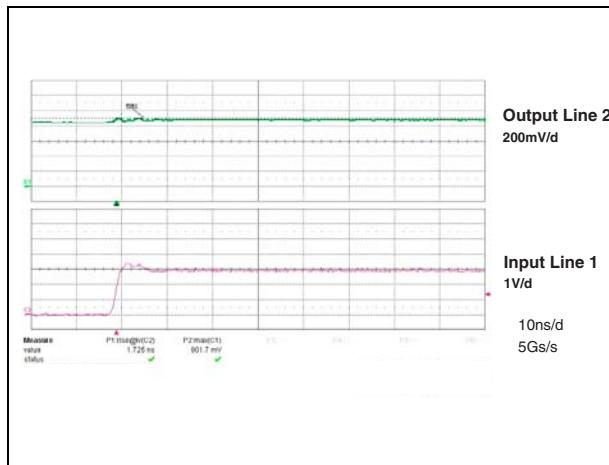
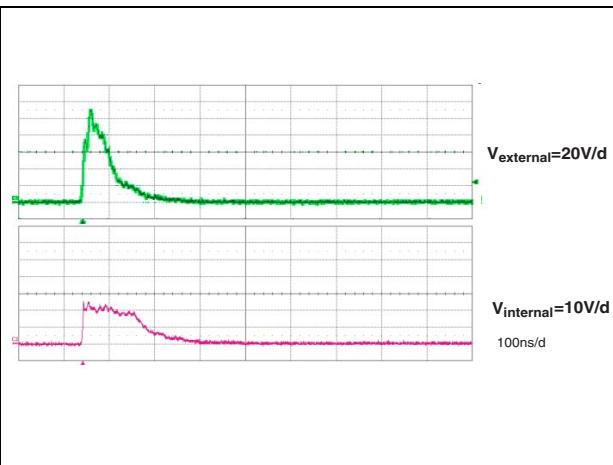
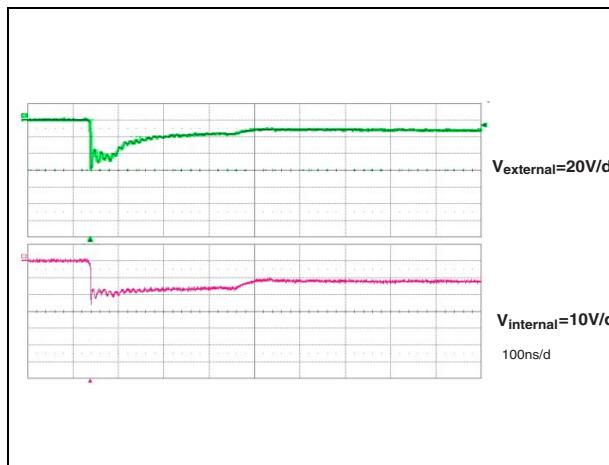
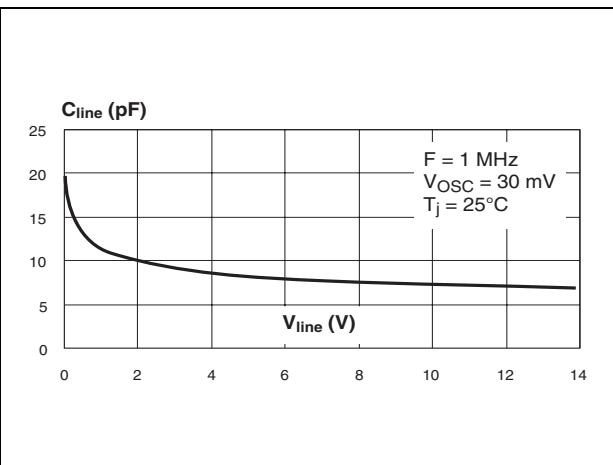
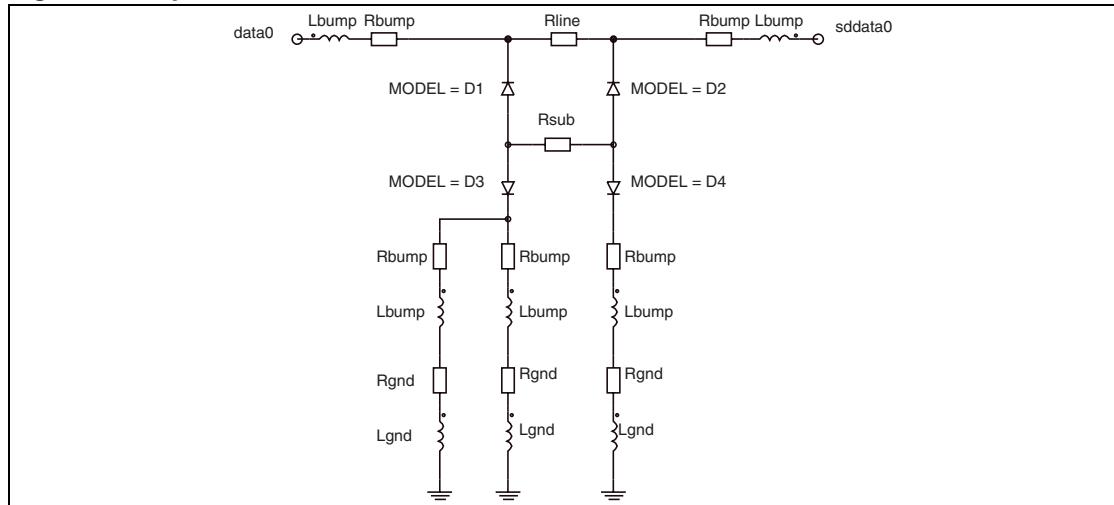
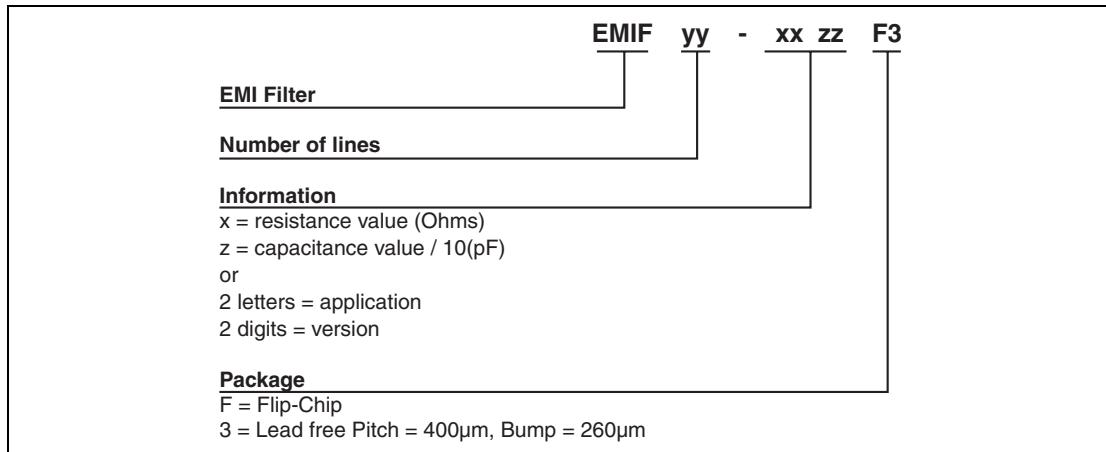
Figure 4. Digital crosstalk measurement**Figure 5. ESD response to IEC61000-4-2 (+15kV air discharge) on one input (V_{IN}) and on one output (V_{OUT})****Figure 6. ESD response to IEC61000-4-2 (-15kV air discharge) on one input (V_{IN}) and on one output (V_{OUT})****Figure 7. Line capacitance versus applied voltage**

Figure 8. Aplac model**Figure 9. Aplac model variables**

<u>Variables</u>	<u>Diode D1</u>	<u>Diode D2</u>	<u>Diode D3</u>	<u>Diode D4</u>
aplacvar Rline 40	BV=7	BV=7	BV=7	BV=7
aplacvar C_d1 14.5p	IBV=1m	IBV=1m	IBV=1m	IBV=1m
aplacvar C_d2 6.5p	CJO=C_d1	CJO=C_d2	CJO=C_d3	CJO=C_d4
aplacvar C_d3 303p	M=0.28	M=0.28	M=0.28	M=0.28
aplacvar C_d4 14.5p	RS=1.13	RS=0.8	RS=0.37	RS=1.13
aplacvar Lbump 43pH	VJ=0.6	VJ=0.6	VJ=0.6	VJ=0.6
aplacvar Rbump 17m	TT=100n	TT=100n	TT=100n	TT=100n
aplacvar Cbump 150f				
aplacvar Lgnd 150pH				
aplacvar Rgnd 10m				
aplacvar Rsub 5				

2 Ordering information scheme



3 Package information

Figure 10. Mechanical data

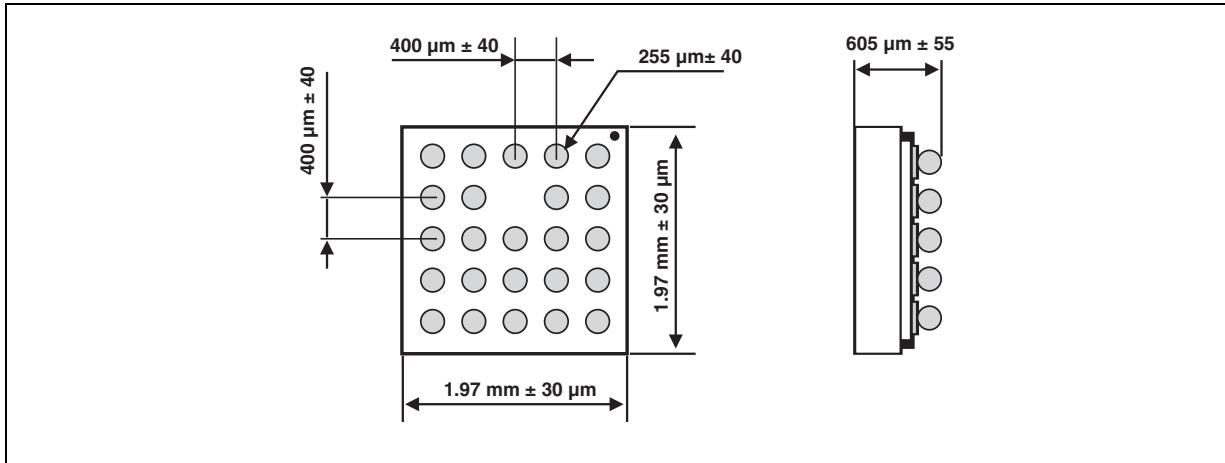


Figure 11. Foot print recommendations

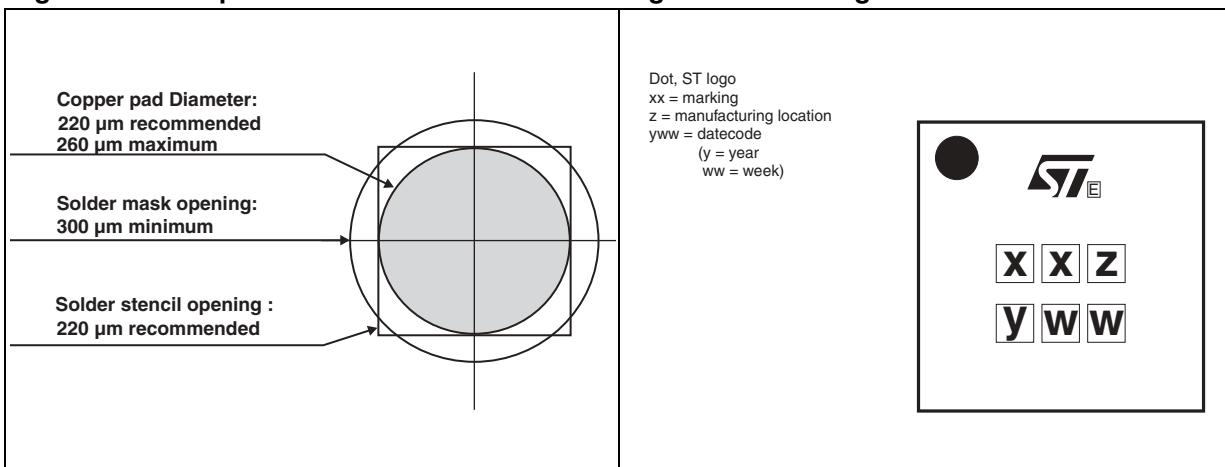


Figure 12. Marking

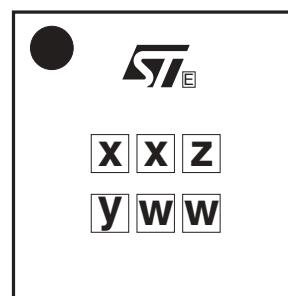
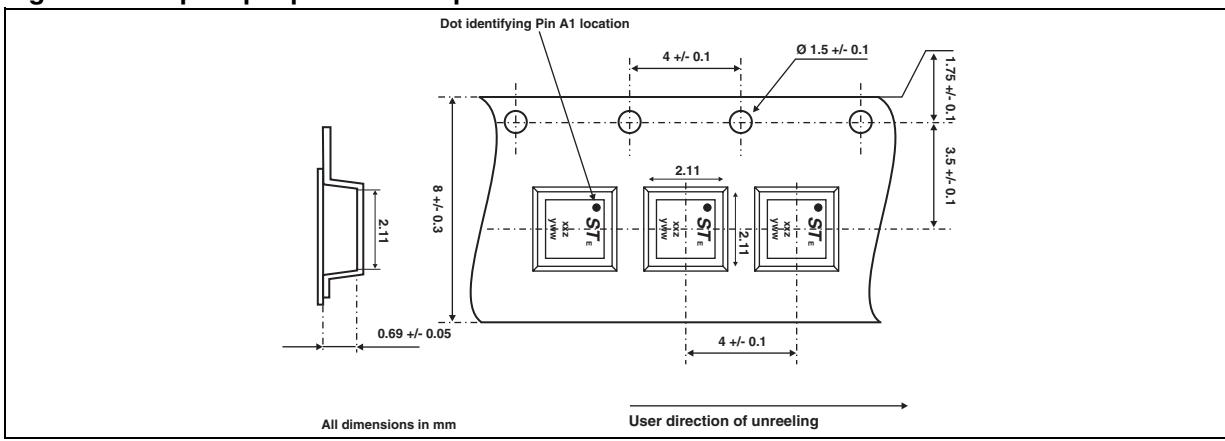


Figure 13. Flip-chip tape and reel specifications



In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com.

4 Ordering information

Part Number	Marking	Package	Weight	Base qty	Delivery mode
EMIF09-SD01F3	GZ	Flip-Chip	5.2 mg	5000	Tape and reel (7")

Note: More information is available in the application note :
AN1235 :"Flip Chip : Package description and recommendations for use"
AN1751 : EMI Filters: Recommendations and measurements

5 Revision history

Date	Revision	Changes
19-Oct-2005	1	Initial release.
09-Feb-2006	2	Tape cavity dimensions added in Figure 13. Other graphics improved.

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